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Docket No.: M4065.0215/P215
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Eugene A. DeLaRosa et al.

Application No.: 09/516,581

Confirmation No.: 3124

Filed: March 1, 2000

Art Unit: 2621

For: METHOD FOR MEASURING
REGISTRATION OF OVERLAPPING
MATERIAL LAYERS OF AN
INTEGRATED CIRCUIT

Examiner: B. P. Werner

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STATUS INQUIRY

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully requested that the attorney named below be advised of the status of the above-identified application. An Office Action was issued on July 15, 2004 and an Amendment in Response to the Non-Final Office Action was filed on October 15, 2004. Please advise us of when we might expect to receive an Office Action from the Patent and Trademark Office responsive to the Amendment filed on October 15, 2004..

Dated: February 15, 2005

Respectfully submitted,

By

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